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| Notice of References Cited | Application/Control No. 09/775,018 | Applicant(s)/Patent Under Reexamination SUDER ET AL. | |
| | Examiner Hanh Nguyen | Art Unit 2662 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-----------------------|----------------|
| | A | US-6,678,280 B1 | 01-2004 | Kim et al. | 370/429 |
| | B | US-6,839,341 B1 | 01-2005 | Nakajima, Yasunori | 370/352 |
| | C | US-6,876,648 B1 | 04-2005 | Lee, Dae-Jin | 370/353 |
| | D | US-5,751,791 | 05-1998 | Chen et al. | 379/88.13 |
| | E | US-5,119,372 A | 06-1992 | Verbeek, Robert J. M. | 370/230 |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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